Docket No.

251154US2SRDX

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Toru TOJO, et al.

SERIAL NO: New Application

GAU:

FILED:

Herewith

EXAMINER:

FOR:

PATTERN INSPECTION APPARATUS

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR.

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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Registration No. 24,913

C. Irvin McClelland Registration Number 21.124

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STATEMENT OF RELEVANCY

Reference AA (5,572,598) of Form PTO-1449:

This reference shows an optical system illuminated by a scanning laser, in which individual transmitted and reflected light and detectors are used to inspect the defects.

Reference AB (5,563,702) of Form PTO-1449:

This reference shows an inspection method using transmitted and reflected signals from the substrate.

Reference AO (2002-501194) of Form PTO-1449:

This reference shows an inspection system which can detect transmitted and reflected light simultaneously.

Reference AW of Form PTO-1449:

The cell-to-cell comparison method to obtain high defect detection sensitivity is studied in this paper. Transmission and reflection optics are used.

Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO.		SERIAL NO.		
(Modified)		PATENT AND TRAI	DEMARK OFFICE	251154US2SRDX		New Application		
				APPLICANT				
LIST OF	REFER	RENCES CITED BY AP	PLICANT	Toru TOJO, et al.				
				FILING DATE		GROUP		
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				U.S. PATENT DOCUMENTS		·		
EXAMINER		DOCUMENT	DATE	NAME CLASS		SUB FILING DATE		
INITIAL		NUMBER	1		CLASS	CLASS	IF APPROPRIATE	
	AA	5,572,598	11/05/96	Mark J. WIHL, et al.				
	AB	5,563,702	10/08/96	David G. EMERY, et al.	<u> </u>			
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	•	OTHER R	EFERENCES	(Including Author, Title, Date, Pertine	nt Pages, e	etc.)		
Yasutaka MORIKAWA, et al., "PERFORMANCE OF CELL-SHIFT DEFECT INSPECTION TECHNIQUE", Proceedings of								
	AW	SPIE, PROTOMASK AND	A-ray Wask	reciniology IV, Vol. 3036, 1337, pgs. 40	ra • 414.			
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	AZ				Additional References sheet(s) attached			
Examiner				, , , , , , , , , , , , , , , , , , , ,	Date Co	Date Considered		
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